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1 Space compaction under generalized mergeability

Das, S.R.; Petriu, E.M.; Barakat, T.F.; Assaf, M.H.; Nayak, A.R.;
Instrumentation and Measurement, IEEE Transactions on, Volume: 47, Issue 5, Oct. 1998
Pages:1283 - 1293

[\[Abstract\]](#) [\[PDF Full-Text \(580 KB\)\]](#) **IEEE JNL**

2 Design of self-testing checkers for Borden codes

Piestrak, S.J.;
Computers, IEEE Transactions on, Volume: 45, Issue: 4, April 1996
Pages:461 - 469

[\[Abstract\]](#) [\[PDF Full-Text \(828 KB\)\]](#) **IEEE JNL**

3 Space compression revisited

Das, S.R.; Barakat, T.F.; Petriu, E.M.; Assaf, M.H.; Chakrabarty, K.;
Instrumentation and Measurement, IEEE Transactions on, Volume: 49, Issue 3, June 2000
Pages:690 - 705

[\[Abstract\]](#) [\[PDF Full-Text \(360 KB\)\]](#) **IEEE JNL**

4 Zero-aliasing space compaction of test responses using multiple part signatures

Chakrabarty, K.; Hayes, J.P.;
Very Large Scale Integration (VLSI) Systems, IEEE Transactions on, Volume: 6, Issue: 2, June 1998
Pages:309 - 313